



SIMS-24

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Tutorial SC1

From Fundamentals to Industrial Applications

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This short course consists of three parts.

In the first part, the fundamentals of SIMS will be discussed. This includes the sputter process, the ion formation process and current theories about ion formation under cluster bombardment.

In the second part, the instrumental options will be discussed. Both, the primary ion bombardment as well as the secondary ion detection will be covered.

In the third part, the short course starts out with describing the special needs when performing SIMS in an industrial context. The course will conclude with the discussion of case studies.